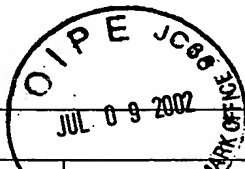


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				Applicants: Das et al.			
				Filing Date: October 26, 2001		Group 1762	
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7	7	DE 198 09 554	9/10/98	Germany ✓	—	—	Abstract
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7	13	JP 11238742	8/31/99	Japan ✓	—	—	Abstract
7	14	JP 11266017	9/28/99	Japan ✓	—	—	Abstract
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7	22	Lipkin et al. "Insulator Investigation on SiC for Improved Reliability," <i>IEEE Transactions on Electron Devices</i> . Vol. 46, No. 3, March 1999, pp. 525-32.	
7	23	Copy of International Search Report for PCT/US01/30715.	

Michael Barr

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